UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of: YAMAGISHI, Yasuo, et al.

Group Art Unit:

Serial No.: 10/621,445

Examiner: Not yet assigned

Filed: **July 18, 2003**

For:

PROBE CARD AND TESTING METHOD OF SEMICONDUCTOR CHIP, CAPACITOR AND MANUFACTURING METHOD THEREOF

INFORMATION DISCLOSURE STATEMENT PURSUANT TO 37 CFR 1.97(b)

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

July 12, 2004

Sir:

The attention of the Patent and Trademark Office is hereby directed to the document listed on the attached Form PTO-1449. One copy of each of the document is attached, together with a copy of an Office Action issued in the corresponding Taiwanese Application.

No fee or certification is required in connection with this Information Disclosure Statement, since it is being submitted prior to the issuance of a first official action on the merits or expiration of the three month period following the filing date or the entry of the national stage of the abovecaptioned application.

The above information is presented so that the Patent and Trademark Office can, in the first instance, determine any materiality thereof to the claimed invention. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the documents cited in the attached Form PTO-1449 be made of record therein and appear on the first page of any patent to issue therefrom.

The Commissioner is authorized to charge our Deposit Account No. 01-2340 for any fee which is deemed by the Patent and Trademark Office to be required to effect consideration of this statement.

Respectfully submitted,

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WGK/nrp Atty. Docket No. **030868** Suite 1000 1725 K Street, N.W. Washington, D.C. 20006 (202) 659-2930

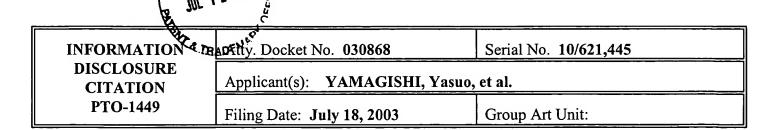
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PATENT TRADEMARK OFFICE

Enclosures:

Office Action issued in corresponding Taiwanese Application

PTO-1449 Reference (1)



U.S. PATENT DOCUMENTS

Examiner Initial		Document No.	Name	Date	Class	Subclass	Filing Date (If appropriate)
	AA	6,218,910	Miller	4/17/01			
	AB						
	AC						
	AD						
	AE						

FOREIGN PATENT DOCUMENTS

		Document No.	Date	Country	Translation (Yes or No)
	AF				
	AG				
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OTHER DOCUMENTS

	AK	
	AL	
Examiner	<u> </u>	Date Considered